

Graphite heat spreader for power component embedded in printed circuit boards (PCB)

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> Introduction to PCB embedding technology.

> Optimization of a graphite heat spreader for PCB.

➤ Experimental validation

➤ Conclusion



Introduction to PCB embedding technology

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[A. Ostmann, 2016]





1.2





- **\diamond** Copper \rightarrow Conventional heat spreader \rightarrow Good thermal conductivity
- * **Diamond** \rightarrow **2000 W/(m K)** isotropic thermal conductivity.
 - \rightarrow Very expensive.
- ♦ Graphite → Orthotropic → 2000 W/(m K) (in-plane).
 → 15 W/(m K) (cross-plane).
 → Not expensive.





Optimization of a graphite heat spreader for PCB

2

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2.1 Graphite heat spreader for PCB: the concept





2.1 Graphite heat spreader for PCB: the concept







Simulations results of and comparison of micro vias patterns:

- Only an eighth was considered due to symmetry to reduce calculation time.
- $\mathbf{k} \mathbf{k} \mathbf{k} \mathbf{k} = \frac{Tav 22^{\circ}C}{Power}$

2.2

Several vias patterns on drain side were compared.





Experimental validation

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3.1 Experimental validation : fabrication



PCB stack :



Copper (35 µm) → 400 W/(mK)

- FR4 (80 μ m _lsola-PCL-FRP-370HR-106) \rightarrow 0.4 W/(mK)
- Graphite (50 µm Panasonic-PGS EYGS12181205) → 1300 W/(mK) (XY)

- The PCB is 45x45mm².
- The active part is 20x20 mm².





1st vias pattern
→ 0.7 mm diameter
and 1.4 mm spacing



2nd vias pattern → 0.7 mm diameter and 2.8 mm spacing



PCB stack-up

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Drilling of mechanical vias

fabrication

3.1 Experimental validation : fabrication



Cross section microscopic images :



Microscopic cross-section pictures: electro-deposited copper of micro-vias in good contact with graphite layers, which is a key point for the proposed stack.

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Diode and connectors soldering :



 Soldering temperature for reflow should be at or above 235°C for a minimal time of 20 seconds.

SiC diode chip (CPW5-1200-Z050B) is used (4.9x4.9 mm²)

Material	CTE-XY (ppm)	CTE-Z (ppm)	Young's Modulus (Gpa)
Isola-PCL-FRP-370HR-106 (FR4)	Pre Tg: 13/14 Post Tg: 14/17	Pre Tg: 45 Post Tg: 230	Grain direction: 25.8 Fill direction: 21.9
Copper (Cu)	16/17	16/17	130
Graphite (Gr) (Panasonic PGS EYGS121805)	0.93	32	~ 2

> Delamination :

- ✤ A delamination took place in graphite samples at places without distributed vias.
- ✤ The delaminate started at 200-220 °C.
- The active part of the sample is still functional because of distributed mechanical vias.











3.2 Experimental validation : experimental setup



- The sample is calibrated in calibration oven to obtain a relationship between junction temperature and diode voltage.
- The test setup measures
 junction-to-case thermal
 resistance (RthJC) using
 the transient dual
 interface method (TDIM).
- All test were performed at heating power of 10 W.





3.3





- Two heating curves are obtained by using a thermal interface material (TIM) of two different thermal resistances.
- The divergence point between the two curves indicates the thermal impedance at which RthJC of the package is considered.
- In this work, one type of TIM is used but with different number of layers to have two different thermal resistances.





3.3

Experimental validation : experimental results







4 Conclusion

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- A heat spreading solution compatible with PCB manufacturing process was proposed by embedding graphite layers in PCB.
- * Numerical simulations predict junction to ambient thermal resistance RthJA reduction of more than 50 %.
- ***** An initial prototype with was fabricated.
 - \rightarrow A delamination took place in samples with graphite following reflow. \rightarrow need for further investigations.
- Thermal experimental results showed a junction to case thermal resistance RthJC reduction of 16-31 % depending on distributed vias pattern.
- ◆ Next step → Tests on a new prototype with embedded chip.



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